

## 1. General description

Planar passivated high commutation three quadrant triac in a SOT78D (TO-220AB) internally insulated plastic package intended for use in circuits where high static and dynamic  $dV/dt$  and high  $dI/dt$  can occur. This triac will commutate the full RMS current at the maximum rated junction temperature ( $T_{j(max)} = 150\text{ °C}$ ) without the aid of a snubber. It is used in applications where "high junction operating temperature capability" is required.

## 2. Features and benefits

- 3Q technology for improved noise immunity
- High commutation capability with maximum false trigger immunity
- High junction operating temperature capability ( $T_{j(max)} = 150\text{ °C}$ )
- High voltage capability
- High current capability
- Less sensitive gate for highest noise immunity
- Internally insulated package
- Internally isolated mounting base
- Triggering in three quadrants only
- Very high immunity to false turn-on by  $dV/dt$  and IEC 61000-4-4 fast transient
- Package is RoHS compliant
- Package meets UL94V0 flammability requirement
- Package meets UL1557 isolation test requirement rated at 2500V RMS

## 3. Applications

- Heating controls
- High power motor control
- High power switching
- Applications subject to high temperature ( $T_{j(max)} = 150\text{ °C}$ )

## 4. Quick reference data

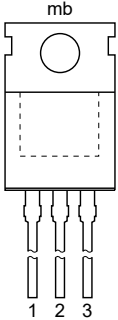
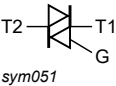
Table 1. Quick reference data

| Symbol       | Parameter                            | Conditions  | Min | Typ | Max | Unit |
|--------------|--------------------------------------|---|-----|-----|-----|------|
| $V_{DRM}$    | repetitive peak off-state voltage    |   | -   | -   | 800 | V    |
| $I_{T(RMS)}$ | RMS on-state current                 | full sine wave; $T_{mb} \leq 86\text{ °C}$ ; <a href="#">Fig. 1</a> ; <a href="#">Fig. 2</a> ; <a href="#">Fig. 3</a> | -   | -   | 30  | A    |
| $I_{TSM}$    | non-repetitive peak on-state current | full sine wave; $T_{j(init)} = 25\text{ °C}$ ; $t_p = 20\text{ ms}$ ; <a href="#">Fig. 4</a> ; <a href="#">Fig. 5</a> | -   | -   | 270 | A    |
|              |                                      | full sine wave; $T_{j(init)} = 25\text{ °C}$ ; $t_p = 16.7\text{ ms}$   | -   | -   | 297 | A    |

| Symbol                  | Parameter                             | Conditions   | Min  | Typ | Max  | Unit |
|-------------------------|---------------------------------------|--|------|-----|------|------|
| T <sub>j</sub>          | junction temperature                  |  | -    | -   | 150  | °C   |
| Static characteristics  |                                       |  |      |     |      |      |
| I <sub>GT</sub>         | gate trigger current                  | V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T2+ G+; T <sub>j</sub> = 25 °C; <a href="#">Fig. 7</a>  | -    | -   | 35   | mA   |
|                         |                                       | V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T2+ G-; T <sub>j</sub> = 25 °C; <a href="#">Fig. 7</a>  | -    | -   | 35   | mA   |
|                         |                                       | V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T2- G-; T <sub>j</sub> = 25 °C; <a href="#">Fig. 7</a>  | -    | -   | 35   | mA   |
| I <sub>H</sub>          | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <a href="#">Fig. 9</a>  | -    | -   | 50   | mA   |
| V <sub>T</sub>          | on-state voltage                      | I <sub>T</sub> = 42 A; T <sub>j</sub> = 25 °C; <a href="#">Fig. 10</a>   | -    | 1.2 | 1.55 | V    |
| Dynamic characteristics |                                       |  |      |     |      |      |
| dV <sub>D</sub> /dt     | rate of rise of off-state voltage     | V <sub>DM</sub> = 536 V; T <sub>j</sub> = 125 °C; (V <sub>DM</sub> = 67% of V <sub>DRM</sub> ); exponential waveform; gate open circuit                  | 2000 | -   | -    | V/μs |
|                         |                                       | V <sub>DM</sub> = 536 V; T <sub>j</sub> = 150 °C; (V <sub>DM</sub> = 67% of V <sub>DRM</sub> ); exponential waveform; gate open circuit                  | 1000 | -   | -    | V/μs |
| dI <sub>com</sub> /dt   | rate of change of commutating current | V <sub>D</sub> = 400 V; T <sub>j</sub> = 125 °C; I <sub>T(RMS)</sub> = 30 A; dV <sub>com</sub> /dt = 20 V/μs; (snubberless condition); gate open circuit | 16   | -   | -    | A/ms |
|                         |                                       | V <sub>D</sub> = 400 V; T <sub>j</sub> = 150 °C; I <sub>T(RMS)</sub> = 30 A; dV <sub>com</sub> /dt = 20 V/μs; (snubberless condition); gate open circuit | 13   | -   | -    | A/ms |

5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description             | Simplified outline  | Graphic symbol  |
|-----|--------|-------------------------|---|---|
| 1   | T1     | main terminal 1         |  | <br>sym051 |
| 2   | T2     | main terminal 2         |   |   |
| 3   | G      | gate                    |   |   |
| mb  | n.c.   | mounting base; isolated |   |   |
|     |        |                         | TO-220AB (SOT78D)   |   |

6. Ordering information

Table 3. Ordering information

| Type number   | Package  |   |         |
|---------------|----------|---|---------|
|               | Name     | Description   | Version |
| BTA330Y-800CT | TO-220AB | plastic single-ended package; isolated heatsink mounted; 1 mounting hole; 3-lead TO-220 | SOT78D  |

7. Limiting values

Table 4. Limiting values  
In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol              | Parameter                            | Conditions   | Min | Max   | Unit             |
|---------------------|--------------------------------------|--|-----|-------|------------------|
| V <sub>DRM</sub>    | repetitive peak off-state voltage    |  | -   | 800   | V                |
| I <sub>T(RMS)</sub> | RMS on-state current                 | full sine wave; T <sub>mb</sub> ≤ 86 °C; Fig. 1; Fig. 2; Fig. 3                      | -   | 30    | A                |
| I <sub>TSM</sub>    | non-repetitive peak on-state current | full sine wave; T <sub>j(init)</sub> = 25 °C; t <sub>p</sub> = 20 ms; Fig. 4; Fig. 5 | -   | 270   | A                |
|                     |                                      | full sine wave; T <sub>j(init)</sub> = 25 °C; t <sub>p</sub> = 16.7 ms               | -   | 297   | A                |
| I <sup>2</sup> t    | I <sup>2</sup> t for fusing          | t <sub>p</sub> = 10 ms; sine-wave pulse  | -   | 364.5 | A <sup>2</sup> s |
| di <sub>T</sub> /dt | rate of rise of on-state current     | I <sub>G</sub> = 70 mA   | -   | 100   | A/μs             |
| I <sub>GM</sub>     | peak gate current                    |  | -   | 2     | A                |
| P <sub>GM</sub>     | peak gate power                      |  | -   | 5     | W                |
| P <sub>G(AV)</sub>  | average gate power                   | over any 20 ms period  | -   | 0.5   | W                |
| T <sub>stg</sub>    | storage temperature                  |  | -40 | 150   | °C               |
| T <sub>j</sub>      | junction temperature                 |  | -   | 150   | °C               |

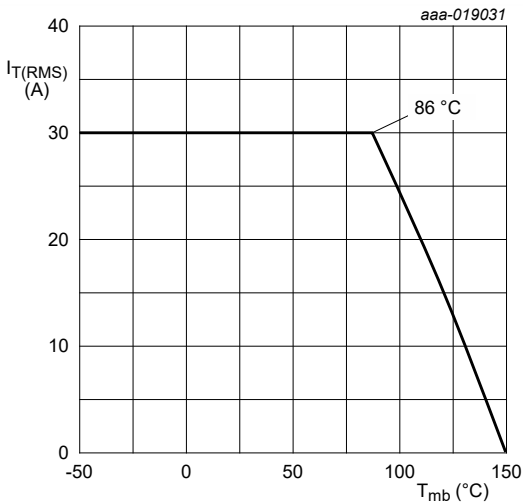


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values

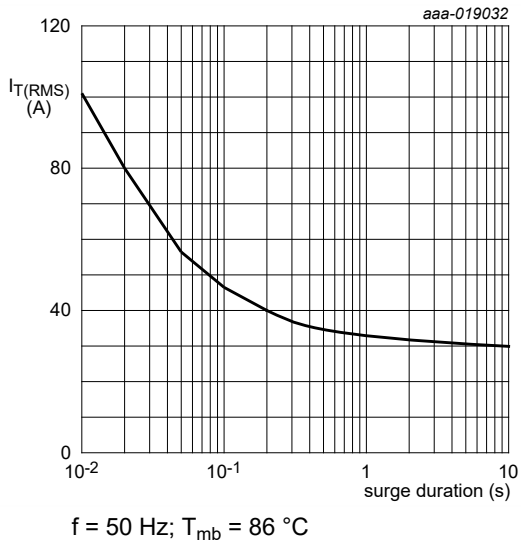


Fig. 2. RMS on-state current as a function of surge duration; maximum values  
f = 50 Hz; T<sub>mb</sub> = 86 °C

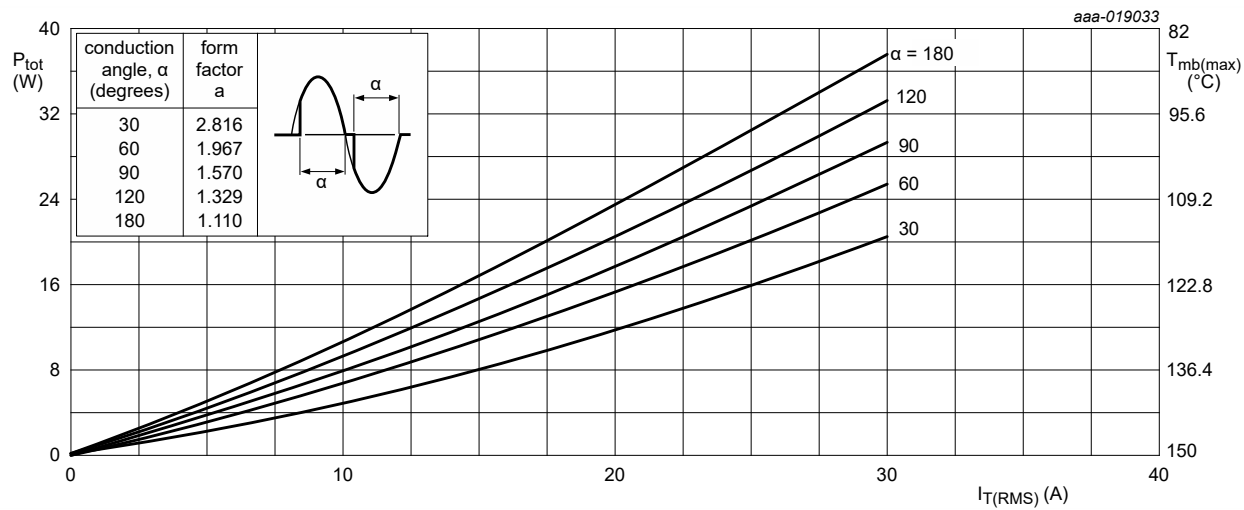


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

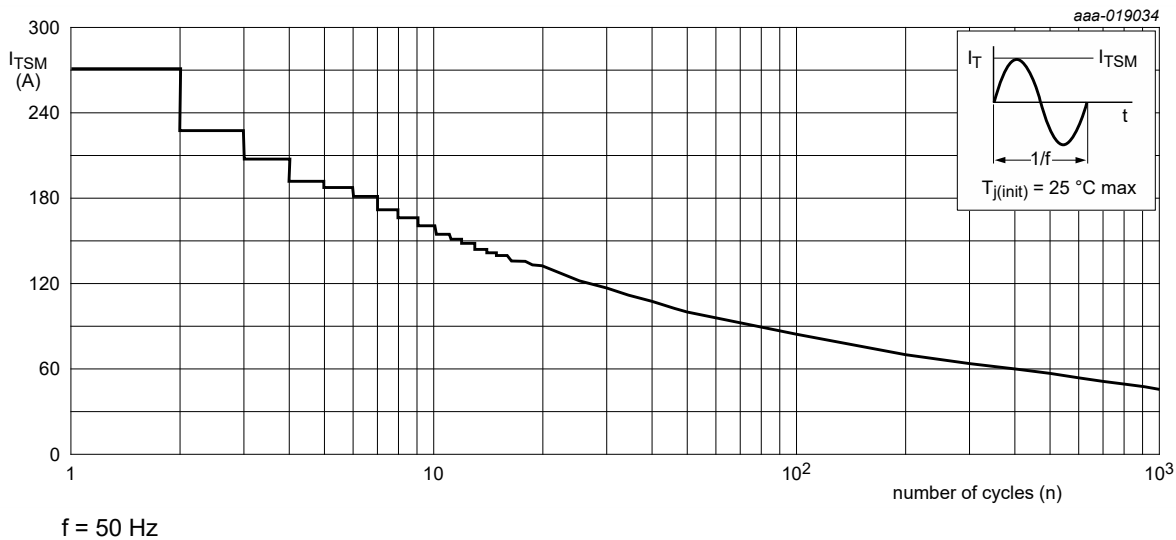
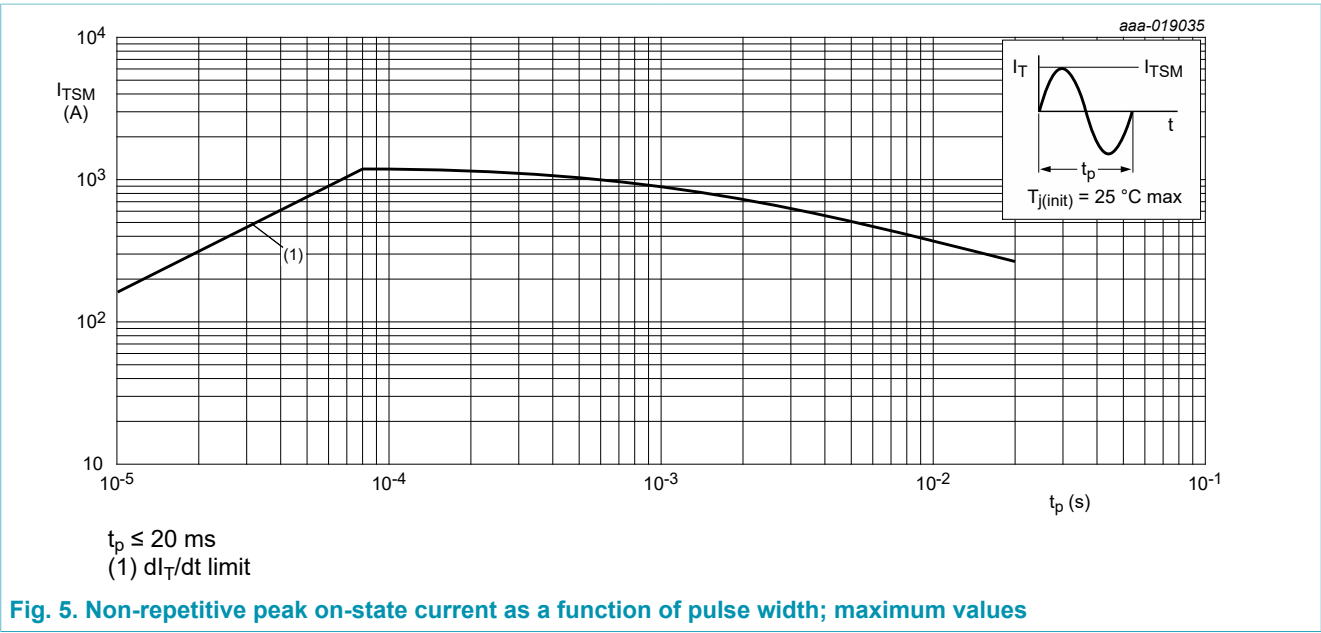


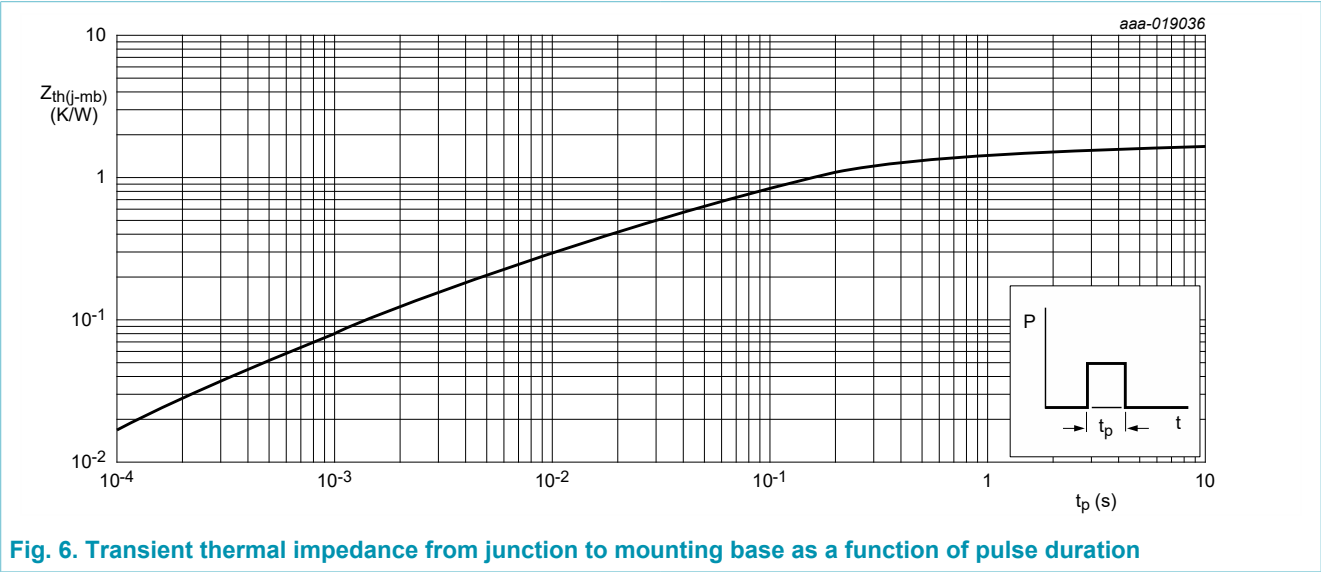
Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



8. Thermal characteristics

Table 5. Thermal characteristics

| Symbol         | Parameter  | Conditions         | Min | Typ | Max | Unit |
|----------------|--|--------------------|-----|-----|-----|------|
| $R_{th(j-mb)}$ | thermal resistance from junction to mounting base    | full cycle; Fig. 6 | -   | -   | 1.7 | K/W  |
| $R_{th(j-a)}$  | thermal resistance from junction to ambient free air | in free air        | -   | 60  | -   | K/W  |



9. Isolation characteristics

Table 6. Isolation characteristics

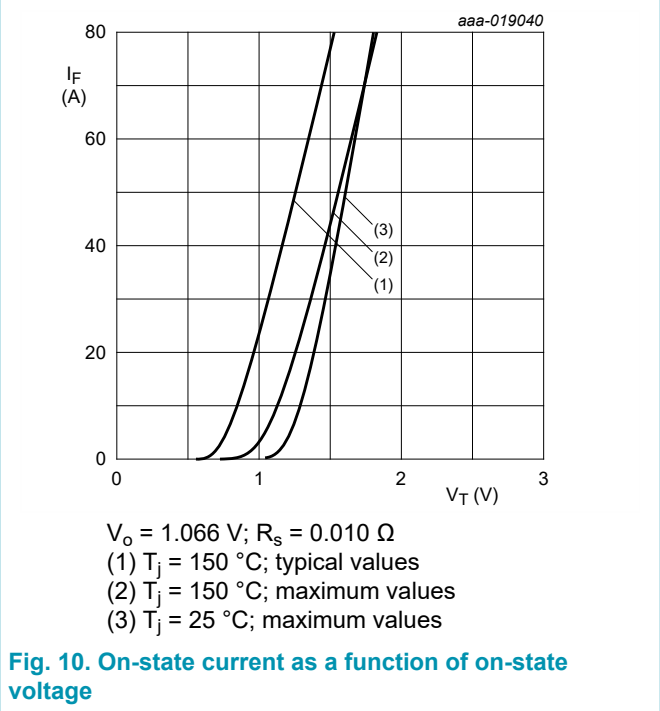
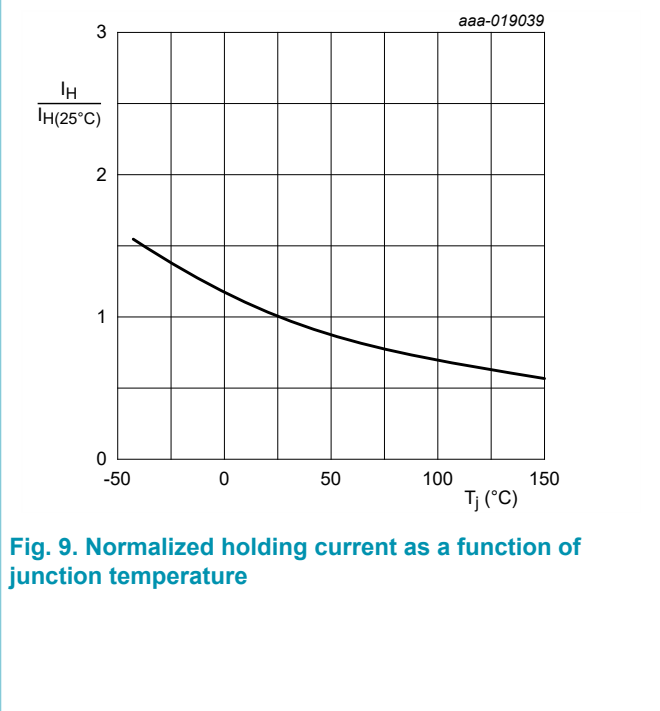
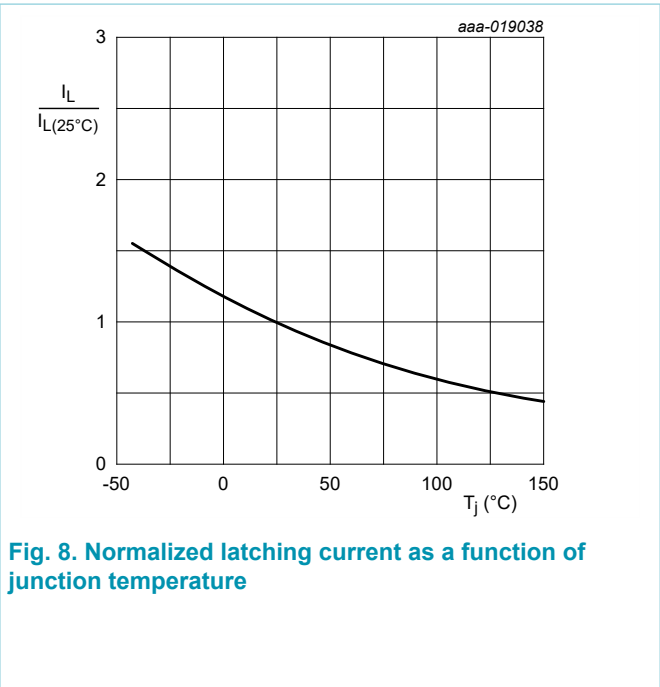
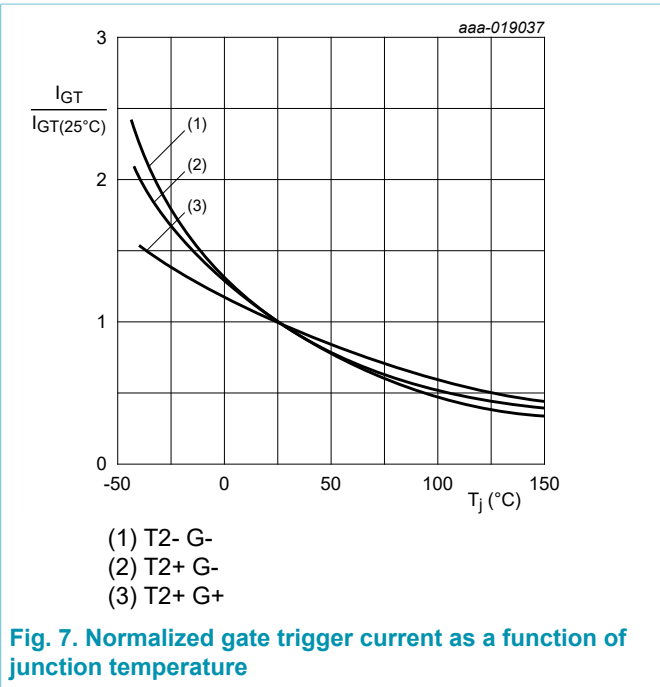
| Symbol          | Parameter             | Conditions  | Min | Typ | Max  | Unit |
|-----------------|-----------------------|---|-----|-----|------|------|
| $V_{isol(RMS)}$ | RMS isolation voltage | from all terminals to external heatsink; sinusoidal waveform; clean and dust free; $50\text{ Hz} \leq f \leq 60\text{ Hz}$ ; $RH \leq 65\%$ ; $T_{mb} = 25\text{ }^{\circ}\text{C}$ | -   | -   | 2500 | V    |
| $C_{isol}$      | isolation capacitance | from main terminal 2 to external heatsink; $f = 1\text{ MHz}$ ; $T_{mb} = 25\text{ }^{\circ}\text{C}$   | -   | 10  | -    | pF   |

## 10. Characteristics

Table 7. Characteristics

| Symbol                  | Parameter                             | Conditions   |  | Min  | Typ  | Max  | Unit |
|-------------------------|---------------------------------------|--|--|------|------|------|------|
| Static characteristics  |                                       |  |  |      |      |      |      |
| I <sub>GT</sub>         | gate trigger current                  | V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T2+ G+; T <sub>j</sub> = 25 °C; <a href="#">Fig. 7</a>  |  | -    | -    | 35   | mA   |
|                         |                                       | V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T2+ G-; T <sub>j</sub> = 25 °C; <a href="#">Fig. 7</a>  |  | -    | -    | 35   | mA   |
|                         |                                       | V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T2- G-; T <sub>j</sub> = 25 °C; <a href="#">Fig. 7</a>  |  | -    | -    | 35   | mA   |
| I <sub>L</sub>          | latching current                      | V <sub>D</sub> = 12 V; I <sub>G</sub> = 0.1 A; T2+ G+; T <sub>j</sub> = 25 °C; <a href="#">Fig. 8</a>  |  | -    | -    | 70   | mA   |
|                         |                                       | V <sub>D</sub> = 12 V; I <sub>G</sub> = 0.1 A; T2+ G-; T <sub>j</sub> = 25 °C; <a href="#">Fig. 8</a>  |  | -    | -    | 100  | mA   |
|                         |                                       | V <sub>D</sub> = 12 V; I <sub>G</sub> = 0.1 A; T2- G-; T <sub>j</sub> = 25 °C; <a href="#">Fig. 8</a>  |  | -    | -    | 70   | mA   |
| I <sub>H</sub>          | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <a href="#">Fig. 9</a>  |  | -    | -    | 50   | mA   |
| V <sub>T</sub>          | on-state voltage                      | I <sub>T</sub> = 42 A; T <sub>j</sub> = 25 °C; <a href="#">Fig. 10</a>   |  | -    | 1.2  | 1.55 | V    |
| V <sub>GT</sub>         | gate trigger voltage                  | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <a href="#">Fig. 11</a>   |  | -    | 0.9  | 1.3  | V    |
|                         |                                       | V <sub>D</sub> = 400 V; T <sub>j</sub> = 150 °C; <a href="#">Fig. 11</a>   |  | 0.2  | 0.45 | -    | V    |
| I <sub>D</sub>          | off-state current                     | V <sub>D</sub> = 800 V; T <sub>j</sub> = 25 °C   |  | -    | -    | 10   | μA   |
|                         |                                       | V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C  |  | -    | 0.4  | 2    | mA   |
| Dynamic characteristics |                                       |  |  |      |      |      |      |
| dV <sub>D</sub> /dt     | rate of rise of off-state voltage     | V <sub>DM</sub> = 536 V; T <sub>j</sub> = 125 °C; (V <sub>DM</sub> = 67% of V <sub>DRM</sub> ); exponential waveform; gate open circuit                  |  | 2000 | -    | -    | V/μs |
|                         |                                       | V <sub>DM</sub> = 536 V; T <sub>j</sub> = 150 °C; (V <sub>DM</sub> = 67% of V <sub>DRM</sub> ); exponential waveform; gate open circuit                  |  | 1000 | -    | -    | V/μs |
| dI <sub>com</sub> /dt   | rate of change of commutating current | V <sub>D</sub> = 400 V; T <sub>j</sub> = 125 °C; I <sub>T(RMS)</sub> = 30 A; dV <sub>com</sub> /dt = 20 V/μs; (snubberless condition); gate open circuit |  | 16   | -    | -    | A/ms |
|                         |                                       | V <sub>D</sub> = 400 V; T <sub>j</sub> = 150 °C; I <sub>T(RMS)</sub> = 30 A; dV <sub>com</sub> /dt = 20 V/μs; (snubberless condition); gate open circuit |  | 13   | -    | -    | A/ms |





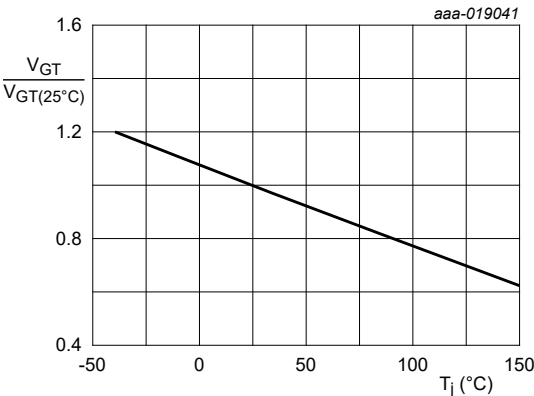


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

11. Package outline

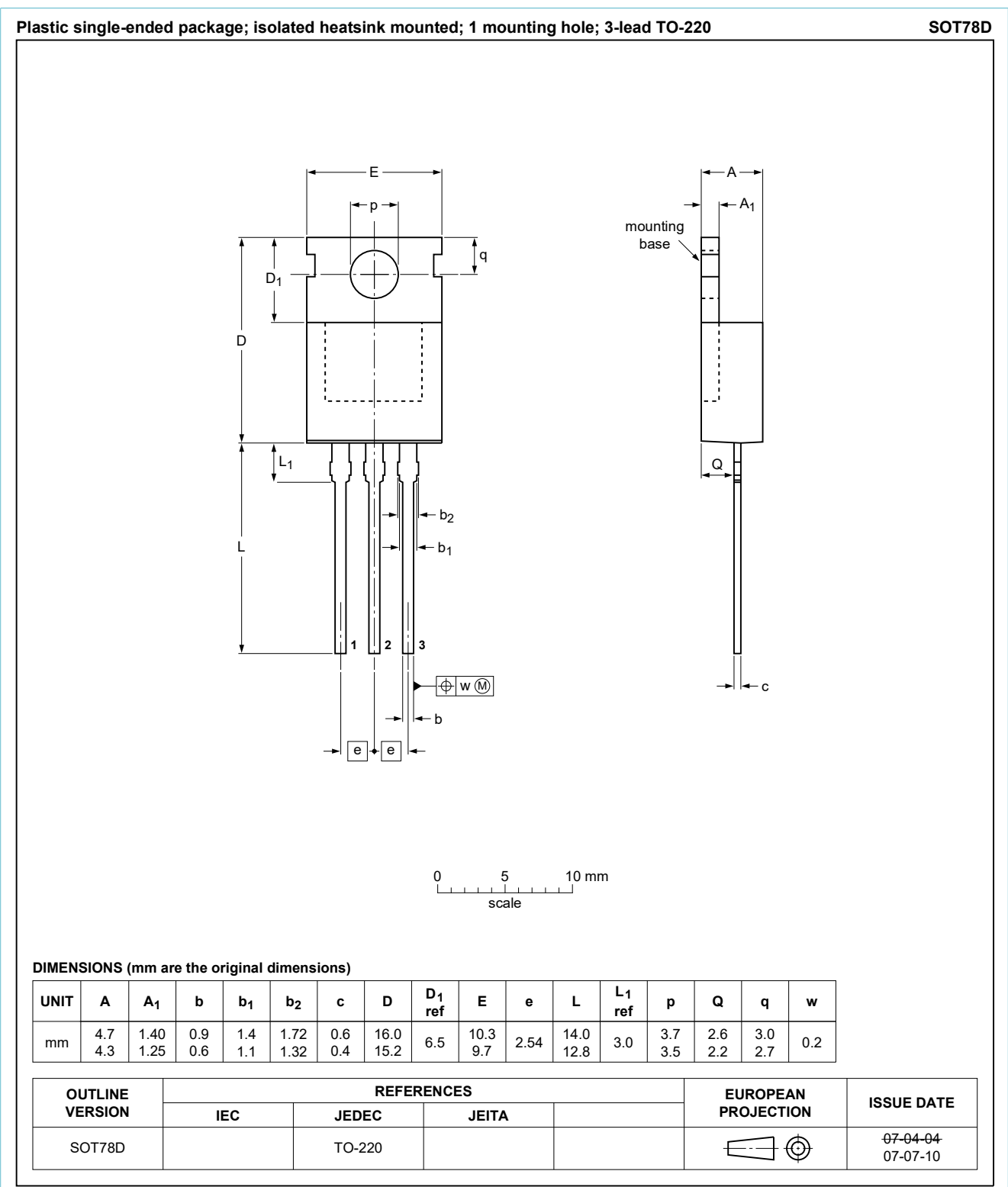


Fig. 12. Package outline TO-220AB (SOT78D)

## 12. Legal information

### Data sheet status

| Document status [1][2]         | Product status [3] | Definition  |
|--------------------------------|--------------------|---|
| Objective [short] data sheet   | Development        | This document contains data from the objective specification for product development. |
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| Product [short] data sheet     | Production         | This document contains the product specification.                                     |

- [1] Please consult the most recently issued document before initiating or completing a design.
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